

DAC80516 16-Channel, 16-Bit, Voltage-Output DAC With Internal Reference

1 Features

- Performance:
	- INL: ±2LSB maximum at 16-bit resolution
	- $-$ TUF: $+0.15\%$ of FSR maximum
- Integrated 2.5V precision internal reference
	- Initial accuracy: ±2.5mV maximum
	- Drift: 5ppm/°C typical
- High drive capability: 50mA with 0.5V from supply rails
- Flexible configuration options
	- User selectable gain: 2 ×, 1 ×
	- Reset to zero scale
	- Clear output function
- Wide operating range:
	- Power supply: 2.7V to 5.5V
	- Temperature range: –40°C to +125°C
- SPI and I²C interfaces: 1.7V to 5.5V operation
- SPI: 4-wire interface
	- I²C: Four target addresses
- Small package:
	- 4mm × 4mm, 28-pin WQFN

2 Applications

- **[Optical modules](https://www.ti.com/solution/optical-module)**
- [Inter-DC interconnect](https://www.ti.com/solution/inter-dc-interconnect-long-haul-submarine)
- [Analog output module](https://www.ti.com/solution/analog-output-module?variantid=14280&subsystemid=15788#block-diagram)

3 Description

The 16-bit DAC80516 is a low-power, 16-channel, buffered voltage-output digital-to-analog converter (DAC). The DAC80516 includes a 2.5V, 5ppm/°C internal reference, eliminating the need for an external precision reference in most applications. A user selectable gain configuration can be used to provide full-scale output voltages of 2.5V or 5V. The DAC80516 operates from a single power supply.

Communication to the DAC80516 is performed through an SPI- and 1^2 C-supported serial interface, operating at clock rates of up to 50MHz (during SPI writes to the device). The VIO pin enables serial interface operation from 1.7V to 5.5V. The DAC80516 flexible interface enables operation with a wide range of industry-standard microprocessors and microcontrollers.

The DAC80516 is characterized for operation over the temperature range of –40°C to +125°C and available in a small WQFN package.

Package Information

(1) For more information, see [Section 11](#page-61-0).

 (2) The package size (length \times width) is a nominal value and includes pins, where applicable.

Functional Block Diagram

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4 Pin Configuration and Functions

Figure 4-1. RUY Package, 28-Pin WQFN (Top View)

Table 4-1. Pin Functions

5 Specifications

5.1 Absolute Maximum Ratings

over operating free-air temperature range (unless otherwise noted) (1)

(1) Operation outside the *Absolute Maximum Ratings* may cause permanent device damage. *Absolute Maximum Ratings* do not imply functional operation of the device at these or any other conditions beyond those listed under *Recommended Operating Conditions*. If used outside the *Recommended Operating Conditions* but within the *Absolute Maximum Ratings*, the device may not be fully functional, and this may affect device reliability, functionality, performance, and shorten the device lifetime.

5.2 ESD Ratings

(1) JEDEC document JEP155 states that 500V HBM allows safe manufacturing with a standard ESD control process.

(2) JEDEC document JEP157 states that 250V CDM allows safe manufacturing with a standard ESD control process.

5.3 Recommended Operating Conditions

over operating free-air temperature range (unless otherwise noted)

5.4 Thermal Information

(1) For more information about traditional and new thermal metrics, see the *[Semiconductor and IC Package Thermal Metrics](https://www.ti.com/lit/pdf/SPRA953)* application report.

5.5 Electrical Characteristics

at T_J = –40°C to +125°C, AV_{DD} = 2.7V to 5.5V, V_{IO} = 1.7V to AV_{DD}, V_{REFIN} = 2.4V to 5.5V, DAC outputs unloaded, and digital inputs at V_{1O} or GND (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
STATIC PERFORMANCE (1)						
	Resolution		16			Bits
INL	Relative accuracy			±1	±2	LSB
DNL	Differential nonlinearity		-1	± 0.6	$\mathbf{1}$	LSB
TUE	Total unadjusted error	DAC output range $= 0V$ to 5V		±0.04	±0.15	%FSR
	Offset error	Gain = 1 or 2		±0.75	±3	mV
	Zero-scale error	DAC register loaded with all zeroes	Ω	0.5	3	mV
	Full-scale error	DAC register loaded at full-scale code (65535d), DAC output range = $0V$ to $5V$		±0.04	±0.15	%FSR
	Gain error	Gain = 1 or 2		±0.04	±0.15	%FSR
	Offset error drift			±3		μ V/°C
	Zero-scale error drift			±2		μ V/°C
	Full-scale error drift			±3		ppm FSR/°C
	Gain error drift			±2		ppm FSR/°C
	Output voltage drift over time	$T_J = 25^{\circ}C$, DAC code = midscale, 1900 hours		20		ppm FSR
OUTPUT CHARACTERISTICS						
	Output voltage ⁽²⁾	$Gain = 2$	$\mathbf 0$		$2 \times V_{REF}$	\vee
		Gain = 1	Ω		V _{REF}	
	Output voltage headroom	To AV _{DD} (-50mA \leq I_{OUT} \leq 50mA), DAC code = full-scale	0.5			\vee
	Load current			50		mA
	Short-circuit current ⁽³⁾	Full-scale output shorted to GND		75		mA
		Zero-scale output shorted to V _{DD}		75		
	Capacitive load ⁽⁴⁾	R_{LOAD} = open	$\mathbf 0$		$\overline{2}$	nF
	DC output impedance	DAC output at AV _{DD} /2		0.08		Ω
		DAC output at AV _{DD} or GND		10		
DYNAMIC PERFORMANCE						
	Output voltage settling time	$\frac{1}{4}$ to $\frac{3}{4}$ scale and $\frac{3}{4}$ to $\frac{1}{4}$ scale settling time to ± 2 LSB, AV _{DD} = 5.5V, V_{REFIN} = 2.5V, gain = 2		6		μs
	Slew rate	$AV_{DD} = 5.5V$, $V_{REFIN} = 2.5V$		1.7		$V/\mu s$
	Power-on glitch magnitude	DAC code = zero scale		25		mV
	Output noise	0.1Hz to 10Hz, DAC code = midscale		12		µVpp
	Output noise density	1kHz, DAC code = midscale, $AV_{DD} = 5.5V$, $V_{REFIN} = 2.5V$		65		nV/Hz
	AC PSRR	DAC code = midscale, frequency = 60Hz, amplitude 200mVpp superimposed on AV _{DD}		80		dB
	DC PSRR	DAC code = midscale, $AV_{DD} = 5V \pm 0.5V$		0.02		mV/V
	Code change glitch impulse	1LSB change around major carrier		$\mathbf 1$		nV-s
	Channel-to-channel ac crosstalk	DAC code = zero scale, full-scale swing on adjacent channel		1		nV-s

5.5 Electrical Characteristics (continued)

at T_J = –40°C to +125°C, AV_{DD} = 2.7V to 5.5V, V_{IO} = 1.7V to AV_{DD}, V_{REFIN} = 2.4V to 5.5V, DAC outputs unloaded, and digital inputs at V_{IO} or GND (unless otherwise noted)

(1) End point fit between codes 256 to 65280

(2) When using an external reference $V_{REF} = V_{REFIN}$. Otherwise, $V_{REF} = 2.5V$ (internal reference voltage)

(3) Temporary overload condition protection. Junction temperature can be exceeded during current limit. Operation at temperatures greater than the specified maximum junction temperature can impair device reliability.

(4) Specified by design and characterization, not production tested.

(5) For a further period of time equal to approximately 5ms, SPI or I2C communication to the device is blocked while the device loads internal calibration coefficients from memory. Any digital communication during this timeframe is ignored.

5.6 Timing Requirements - I2C Standard Mode

at T_J = –40°C to +125°C, AV_{DD} = 2.7V to 5.5V, V_{IO} = 1.7V to AV_{DD}, V_{REFIN} = 2.4V to 5.5V, and digital inputs at V_{IO} or GND

5.7 Timing Requirements - I2C Fast Mode

5.8 Timing Requirements - I2C Fast Mode Plus

at T_J = –40°C to +125°C, AV_{DD} = 2.7V to 5.5V, V_{IO} = 1.7V to AV_{DD}, V_{REFIN} = 2.4V to 5.5V, and digital inputs at V_{IO} or GND

5.9 Timing Requirements - SPI

(1) Write operations to the device can be performed at frequencies up to 50MHz.

5.10 Switching Characteristics

at T_J = –40°C to +125°C, AV_{DD} = 2.7V to 5.5V, V_{IO} = 1.7V to AV_{DD}, V_{REFIN} = 2.4V to 5.5V, DAC outputs unloaded, and digital inputs at V_{IO} or GND

5.11 Timing Diagrams

Figure 5-2. SPI Timing Diagram

5.12 Typical Characteristics

6 Detailed Description

6.1 Overview

The DAC80516 is a low-power, sixteen-channel, buffered voltage-output digital-to-analog converter (DAC) with 16-bit resolution. The DAC80516 includes a 2.5V internal reference and provides user-selectable gain configuration through software, which can be used to set the full-scale output voltage range for groups of four DACs at a time (see also [Section 6.3.1.1\)](#page-19-0). The device operates from a single 2.7V to 5.5V supply. Communication to the DAC80516 is performed through a serial interface that supports SPI and I²C communication.

The DAC80516 incorporates a power-on-reset circuit that powers up and maintains the DAC outputs at zero scale until a valid code is written to the device.

A clear pin enables a simultaneous update of multiple DAC channels to specified clear values.

6.2 Functional Block Diagram

6.3 Feature Description

6.3.1 Digital-to-Analog Converter (DAC) Architecture

Each output channel in the DAC80516 consists of an R-2R ladder architecture followed by an output buffer amplifier. Figure 6-1 shows a block diagram of the DAC architecture.

Figure 6-1. DAC80516 DAC Block Diagram

After a reset event, all the DAC registers are set to code 0x0000, the DAC output amplifiers are powered down, and the DAC outputs are clamped to GND. Each DAC output can be independently enabled or disabled through software by writing to the appropriate bit of the PWDWN register. When disabled, the DAC output is clamped to ground via a pull-down resistor.

6.3.1.1 DAC Register Structure

The DAC produces output voltages proportional to a 16-bit input data code. Input data are written to the DAC data register in straight binary format for all output ranges. By writing to the DAC_GAIN register, the user can configure the maximum full-scale DAC output voltage as either $1 \times V_{REF}$ or $2 \times V_{REF}$ (maximum of 5V), where V_{REF} is the internal or external reference input voltage. [Section 7.1.5 s](#page-32-0)hows that the gain settings can be configured for QUAD0 (OUT0 through OUT3), QUAD1 (OUT4 through OUT7), QUAD2 (OUT8 through OUT11) and QUAD3 (OUT12 through OUT15); all DAC channels in a QUAD group share the same gain settings.

Data written to the DAC data registers are initially stored in the DAC buffer registers. The transfer of data from the DAC buffer registers to the DAC active registers can be configured to happen immediately (asynchronous mode) or initiated by a DAC trigger signal (synchronous mode). When the DAC active registers are updated, the DAC output channels change to the new values.

By setting the corresponding BCAST_EN bits in the DAC_BCAST_EN register, each DAC can be configured to operate in broadcast mode. When a value is written to the BCAST DAC DATA register, this value is automatically stored in the buffer and active data registers of all DACs operating in broadcast mode.

Additionally, each DAC has a short circuit detection circuit. The DAC_STATUS register indicates which DAC channels are presently in short-circuit condition. A global status bit (GDAC_SC_STS, in the STATUS register) is the logical OR of all the DAC_STATUS bits, which can be used to determine if there is at least one channel in the short circuit condition.

6.3.1.1.1 DAC Synchronous Operation

The update mode for each DAC channel is determined by the DAC synchronous setting, configured for each DAC by writing to the SYNC_EN register. In asynchronous mode, a write to the DAC buffer data register results in an immediate update of the DAC active registers on a \overline{CS} rising edge. In synchronous mode, writing to the DAC buffer data register does not automatically update the DAC active register. Instead, the update occurs only after a DAC trigger signal is generated. A DAC trigger signal can be generated by pulling the LDAC pin low, which updates the active registers of all DAC output channels operating in synchronous mode simultaneously. The LDAC pin does not affect the active registers of channels already configured as asynchronous in the SYNC_EN register; however all other channels (configured as synchronous in the SYNC_EN register) operate in asynchronous mode as long as the LDAC pin is held at logic low. A DAC trigger can also be generated through software, by writing to the appropriate LDAC OUTn bit in the TRIGGER register. A software trigger updates the active registers of two DAC channels at a time; each bit in the TRIGGER register corresponds to a pair of output channels, and setting a bit to 1 updates both corresponding channels simultaneously.

6.3.1.1.2 DAC Buffer Amplifier

The DAC output buffer amplifiers are capable of rail-to-rail operation, featuring low noise and low drift voltage output. The amplifier outputs are available at the DAC output pins. The maximum DAC output voltage range is limited by the AV_{DD} supply.

The high output current of the device provides good slewing characteristics even with large capacitive loads. To estimate the positive and negative slew rates for large capacitive loads, divide the source and sink short-circuit current value by the capacitor.

6.3.1.1.3 DAC Transfer Function

The DAC transfer function is given by Equation 1.

$$
V_{\text{DAC}} = \left(\frac{\text{DACIN}}{2^{16}}\right) \times \text{FSR} \tag{1}
$$

where

- DACIN = decimal equivalent of the binary code loaded to the DAC register. DACIN range = 0 to $2^{16} 1$.
- FSR = DAC full-scale output for the selected output range. FSR is 2.5V for the 0V to 2.5V range, and 5V for the 0V to 5V range.

The DAC output spans the voltage ranges shown in Table 6-1.

6.3.2 Internal Reference

The DAC80516 includes a 2.5V precision band-gap reference enabled by default. Operation from an external reference is supported by disabling the internal reference, by writing to the REF_PWDWN bit in the GEN CONFIG register. The internal reference is externally available at the REF pin.

A minimum 150nF capacitor is recommended between the reference output and GND for noise filtering.

6.3.3 Power-On Reset (POR)

The DAC80516 provides a power-on reset (POR) function. After start-up, when the AV_{DD} and V_{IO} supplies have been established, a POR is issued to so that the device initializes correctly (see also [Section 8.3\)](#page-59-0). The DAC80516 requires 5ms to 10ms to initialize the serial interface after a POR; therefore, wait at least 10ms after start-up to communicate with the device.

During operation, the following three conditions can trigger a reset:

- 1. AV_{DD} or V_{IO} decrease to less than the recommended minimum operating value (by at least 200mV)
- 2. A value of 0xA (hexadecimal) is written to the SOFT_RST field in the TRIGGER register
- 3. The RESET pin of the device is pulled to logic 0, for at least 20ns. As long as the pin is held at logic 0, the device remains in a powered-down state until the pin is set to logic 1 (at which time, the device performs initialization of the serial interface again).

6.4 Device Functional Modes

6.4.1 Clear Mode

Each DAC can be set to enter a clear state using either hardware or software. When a DAC enters the clear state, the DAC is loaded with the data stored in the corresponding CLEAR CODE register (code 0 by default) and the output is set to the corresponding voltage level.

The DAC buffer and active registers do not change when the DACs enter the clear state, which enables the DAC to return to the operating point prior to the clear event. The DAC buffer and active registers can also be updated while the DAC is in clear state, thus allowing the DAC to output a new value upon return to normal operation. When the DAC exits the clear state, the DAC is immediately loaded with the data in the active register, and the DAC output channel is set back to the corresponding level to restore operation.

By writing to the appropriate bits in the CLEAR register, each DAC can be programmed to enter or exit the clear state. Each DAC can also be forced to enter a clear state through the FLEXIO pin, when configured as an active-low CLEAR pin. This configuration is done by setting the FLEXIO FUNC bit in the GEN CONFIG register (by default, this bit is 0, and FLEXIO acts as a general purpose input-output pin). By default, each DAC output is automatically cleared when the CLEAR pin is asserted to a logic-low level, unless the appropriate bit in the CLEAR_PIN_MASK register is set. After the DAC leaves the clear state, the DAC is reloaded with the contents of the active register and the DAC output channel updates accordingly.

The device also allows user to set a common clear code for each DAC, which can be done by writing to the BCAST_CLR_DATA register. The value stored in this register is written to the CLEAR_CODE registers of all DACs operating in broadcast mode (determined by the appropriate bit setting in the BCAST_EN register), which can be used to clear multiple DACs channels to the same code simultaneously.

If a DAC channel is in a power-down state for any reason, any clear commands are ignored on the DAC until the channel exits the power-down state.

6.5 Programming

The device communicates with the system controller through a serial interface, which supports either an I²Ccompatible two-wire bus, or an SPI-compatible bus. The device includes a robust mechanism that detects between an SPI-compatible or I²C-compatible controller, and automatically configures the interface accordingly. The interface detection mechanism operates at start-up, thus preventing protocol change during normal operation.

The register map addresses range from 0x00 to 0x32, enabling access of bits within each respective register (see [Section 7](#page-27-0) for additional details).

6.5.1 I ²C Serial Interface

In I²C mode, the device operates only as a target device on the two-wire bus. Connections to either bus are made using the open-drain I/O lines, SDA and SCL. The SDA and SCL pins feature integrated spike suppression filters and Schmitt triggers to minimize the effects of input spikes and bus noise. The device supports the transmission protocol for fast mode as well as fast mode plus. All data bytes are transmitted MSB first.

6.5.1.1 I ²C Bus Overview

The device is I2C compatible. In I2C protocol, the device that initiates the transfer is called a *controller*, and a device controlled by the controller is called a *target*. The bus must be controlled by a controller device that generates the serial clock (SCL), controls the bus access, and generates the START and STOP conditions.

To address a specific device, a START condition is initiated. A START condition is indicated by pulling the data line (SDA) from a high-to-low logic level while SCL is high. All targets on the bus receive the target address byte, with the last bit indicating whether a read or write operation is intended. During the ninth clock pulse, the target being addressed responds to the controller by generating an acknowledge bit and pulling SDA low.

Data transfer is then initiated and sent over eight clock pulses followed by an acknowledge bit. During data transfer, SDA must remain stable while SCL is high because any change in SDA while SCL is high is interpreted as a control signal.

After all data have been transferred, the controller generates a STOP condition. A STOP condition is indicated by pulling SDA from low to high, while SCL is high.

6.5.1.2 I ²C Bus Definitions

The device is I²C-compatible and the bus definitions are listed in Table 6-2.

6.5.1.3 I ²C Target Address Selection

The I²C bus target address is selected by installing shunts from the A0 and A1 pins to the V_{IO} or GND rails. The state of the A0 and A1 pins is tested after every occurrence of START condition on the I²C bus. The device discerns between two possible options for each pin, shunt to V_{1O} (logic 1) and shunt to GND (logic 0), for a total of four possible target addresses, as shown in Table 6-3.

6.5.1.4 I ²C Read and Write Operations

When writing to the device, the value for the address register is the first byte transferred after the target address byte with the R/\overline{W} bit low. Every write operation to the device requires a value for the address register, as shown in Figure 6-2.

From Controller to Target From Target to Controller

Figure 6-2. I ²C Write Access Protocol

When reading from the device, the last value stored in the address register by a write operation is used to determine which register is read by a read operation. To change which register is read for a read operation, a new value must be written to the address register. This transaction is accomplished by issuing a target address byte with the R/ \overline{W} bit low, followed by the address register byte; no additional data are required. The controller can then generate a START condition and send the target address byte with the R/ \overline{W} bit high to initiate the read command.

If repeated reads from the same register are desired, there is no need to continually send the address register bytes because the device retains the address register value until the value is changed by the next write operation. The register bytes are big endian and left justified.

Terminate read operations by issuing a *not-acknowledge* command at the end of the last byte to be read. The controller must leave the SDA line high during the acknowledge time of the last byte that is read from the target, as shown in Figure 6-3.

Figure 6-3. I ²C Read Access Protocol

Block access functionality is provided to minimize the transfer overhead of large data sets. Block access enables multibyte transfers and is configured by setting the block access bit high. Until the transaction is terminated by the STOP condition, the device reads and writes the subsequent memory locations, as shown in Figure 6-4 and Figure 6-5. If the controller reaches address 0x7F in a page, the device continues reading and writing from this address until the transaction is terminated.

Figure 6-5. I ²C Block Read Access

6.5.1.5 I ²C General-Call Reset

The device supports reset using the two-wire general call address 00h (0000 0000b). The device acknowledges the general-call address, and responds to the second byte. If the second byte is 06h (0000 0110b), the device executes a software reset. This software reset initiates a reset event. The device takes no action in response to other values in the second byte.

6.5.2 Serial Peripheral Interface (SPI)

In SPI mode, the device is controlled through a flexible four-wire serial interface that is compatible with SPI-type interfaces used on many microcontrollers and DSP controllers. The interface provides access to the device registers.

6.5.2.1 SPI Bus Overview

A serial interface access cycle is initiated by asserting the CS pin low. The serial clock SCLK can be a continuous or gated clock. SDI data are clocked on SCLK falling edges. A regular serial interface access cycle is 24 bits long, thus the $\overline{\text{CS}}$ pin must stay low for at least 24 SCLK falling edges. The access cycle ends when the CS pin is deasserted high. If the access cycle contains less than the minimum clock edges, the communication is ignored. If the access cycle contains more than the minimum clock edges, only the last 24 bits are used by the device. When CS is high, the SCLK and SDI signals are blocked and the SDO pin is in a Hi-Z state.

In a serial interface access cycle, the first byte input to SDI is the instruction cycle that identifies the request as a read or write command, and the 7-bit address to be accessed. The following bits in the cycle form the data cycle, as shown in Table 6-4.

Table 6-4. SPI Serial Interface Access Cycle

Read operations require that the SDO pin is first enabled by setting the SDO_EN bit. A read operation is initiated by issuing a read command access cycle. After the read command, a second access cycle must be issued to get the requested data, formatted as shown in Table 6-5. Data are clocked out on the SDO pin on SCLK rising or falling edges, according to the FSDO bit setting.

Table 6-5. SDO Output Access Cycle

7 Register Map

Table 7-1. Register Map (continued)

7.1 DAC80516 Registers

7.1.1 NOP Register (Offset = 0h) [Reset = 0000h]

Table 7-2. NOP Register Field Descriptions

7.1.2 DEVICE_ID Register (Offset = 1h) [Reset = 8516h] Figure 7-2. DEVICE_ID Register

Table 7-3. DEVICE_ID Register Field Descriptions

7.1.3 VERSION_ID Register (Offset = 2h) [Reset = 0000h] Figure 7-3. VERSION_ID Register

Table 7-4. VERSION_ID Register Field Descriptions

7.1.4 PWDWN Register (Offset = 3h) [Reset = FFFFh]

Table 7-5. PWDWN Register Field Descriptions

7.1.5 DAC_GAIN Register (Offset = 4h) [Reset = 0000h] Figure 7-5. DAC_GAIN Register

Table 7-6. DAC_GAIN Register Field Descriptions

7.1.6 TRIGGER Register (Offset = 5h) [Reset = 0000h]

Table 7-7. TRIGGER Register Field Descriptions

7.1.7 BCAST_DAC_DATA Register (Offset = 6h) [Reset = 0000h] Figure 7-7. BCAST_DAC_DATA Register

Table 7-8. BCAST_DAC_DATA Register Field Descriptions

7.1.8 STATUS Register (Offset = 7h) [Reset = 4008h] Figure 7-8. STATUS Register

Table 7-9. STATUS Register Field Descriptions

7.1.9 SDO_EN Register (Offset = 8h) [Reset = 0000h]

Table 7-10. SDO_EN Register Field Descriptions

7.1.10 GEN_CONFIG Register (Offset = 9h) [Reset = 0014h] Figure 7-10. GEN_CONFIG Register

Table 7-11. GEN_CONFIG Register Field Descriptions

7.1.11 SYNC_EN Register (Offset = Ah) [Reset = 0000h] Figure 7-11. SYNC_EN Register

Table 7-12. SYNC_EN Register Field Descriptions

Table 7-12. SYNC_EN Register Field Descriptions (continued)

7.1.12 BCAST_EN Register (Offset = Bh) [Reset = FFFFh] Figure 7-12. BCAST_EN Register

Table 7-13. BCAST_EN Register Field Descriptions

7.1.13 CLEAR Register (Offset = Ch) [Reset = 0000h] Figure 7-13. CLEAR Register

Table 7-14. CLEAR Register Field Descriptions

Table 7-14. CLEAR Register Field Descriptions (continued)

7.1.14 CLEAR_PIN_MASK Register (Offset = Dh) [Reset = 0000h] Figure 7-14. CLEAR_PIN_MASK Register

Table 7-15. CLEAR_PIN_MASK Register Field Descriptions

7.1.15 BCAST_CLR_DATA Register (Offset = Eh) [Reset = 0000h] Figure 7-15. BCAST_CLR_DATA Register

Table 7-16. BCAST_CLR_DATA Register Field Descriptions

7.1.16 RESET_FLAGS Register (Offset = Fh) [Reset = 000Fh] Figure 7-16. RESET_FLAGS Register

Table 7-17. RESET_FLAGS Register Field Descriptions

7.1.17 OUT0_BUFFER_CODE Register (Offset = 10h) [Reset = 0000h] Figure 7-17. OUT0_BUFFER_CODE Register

Table 7-18. OUT0_BUFFER_CODE Register Field Descriptions

7.1.18 OUT1_BUFFER_CODE Register (Offset = 11h) [Reset = 0000h] Figure 7-18. OUT1_BUFFER_CODE Register

Table 7-19. OUT1_BUFFER_CODE Register Field Descriptions

7.1.19 OUT2_BUFFER_CODE Register (Offset = 12h) [Reset = 0000h] Figure 7-19. OUT2_BUFFER_CODE Register

Table 7-20. OUT2_BUFFER_CODE Register Field Descriptions

7.1.20 OUT3_BUFFER_CODE Register (Offset = 13h) [Reset = 0000h] Figure 7-20. OUT3_BUFFER_CODE Register

Table 7-21. OUT3_BUFFER_CODE Register Field Descriptions

7.1.21 OUT4_BUFFER_CODE Register (Offset = 14h) [Reset = 0000h] Figure 7-21. OUT4_BUFFER_CODE Register

Table 7-22. OUT4_BUFFER_CODE Register Field Descriptions

7.1.22 OUT5_BUFFER_CODE Register (Offset = 15h) [Reset = 0000h] Figure 7-22. OUT5_BUFFER_CODE Register

Table 7-23. OUT5_BUFFER_CODE Register Field Descriptions

7.1.23 OUT6_BUFFER_CODE Register (Offset = 16h) [Reset = 0000h] Figure 7-23. OUT6_BUFFER_CODE Register

Table 7-24. OUT6_BUFFER_CODE Register Field Descriptions

7.1.24 OUT7_BUFFER_CODE Register (Offset = 17h) [Reset = 0000h] Figure 7-24. OUT7_BUFFER_CODE Register

Table 7-25. OUT7_BUFFER_CODE Register Field Descriptions

7.1.25 OUT8_BUFFER_CODE Register (Offset = 18h) [Reset = 0000h] Figure 7-25. OUT8_BUFFER_CODE Register

Table 7-26. OUT8_BUFFER_CODE Register Field Descriptions

7.1.26 OUT9_BUFFER_CODE Register (Offset = 19h) [Reset = 0000h] Figure 7-26. OUT9_BUFFER_CODE Register

Table 7-27. OUT9_BUFFER_CODE Register Field Descriptions

7.1.27 OUT10_BUFFER_CODE Register (Offset = 1Ah) [Reset = 0000h] Figure 7-27. OUT10_BUFFER_CODE Register

Table 7-28. OUT10_BUFFER_CODE Register Field Descriptions

7.1.28 OUT11_BUFFER_CODE Register (Offset = 1Bh) [Reset = 0000h] Figure 7-28. OUT11_BUFFER_CODE Register

Table 7-29. OUT11_BUFFER_CODE Register Field Descriptions

7.1.29 OUT12_BUFFER_CODE Register (Offset = 1Ch) [Reset = 0000h] Figure 7-29. OUT12_BUFFER_CODE Register

Table 7-30. OUT12_BUFFER_CODE Register Field Descriptions

7.1.30 OUT13_BUFFER_CODE Register (Offset = 1Dh) [Reset = 0000h] Figure 7-30. OUT13_BUFFER_CODE Register

Table 7-31. OUT13_BUFFER_CODE Register Field Descriptions

7.1.31 OUT14_BUFFER_CODE Register (Offset = 1Eh) [Reset = 0000h] Figure 7-31. OUT14_BUFFER_CODE Register

Table 7-32. OUT14_BUFFER_CODE Register Field Descriptions

7.1.32 OUT15_BUFFER_CODE Register (Offset = 1Fh) [Reset = 0000h] Figure 7-32. OUT15_BUFFER_CODE Register

Table 7-33. OUT15_BUFFER_CODE Register Field Descriptions

7.1.33 OUT0_CLEAR_CODE Register (Offset = 20h) [Reset = 0000h] Figure 7-33. OUT0_CLEAR_CODE Register

Table 7-34. OUT0_CLEAR_CODE Register Field Descriptions

7.1.34 OUT1_CLEAR_CODE Register (Offset = 21h) [Reset = 0000h] Figure 7-34. OUT1_CLEAR_CODE Register

Table 7-35. OUT1_CLEAR_CODE Register Field Descriptions

7.1.35 OUT2_CLEAR_CODE Register (Offset = 22h) [Reset = 0000h] Figure 7-35. OUT2_CLEAR_CODE Register

Table 7-36. OUT2_CLEAR_CODE Register Field Descriptions

7.1.36 OUT3_CLEAR_CODE Register (Offset = 23h) [Reset = 0000h] Figure 7-36. OUT3_CLEAR_CODE Register

Table 7-37. OUT3_CLEAR_CODE Register Field Descriptions

7.1.37 OUT4_CLEAR_CODE Register (Offset = 24h) [Reset = 0000h] Figure 7-37. OUT4_CLEAR_CODE Register

Table 7-38. OUT4_CLEAR_CODE Register Field Descriptions

7.1.38 OUT5_CLEAR_CODE Register (Offset = 25h) [Reset = 0000h] Figure 7-38. OUT5_CLEAR_CODE Register

Table 7-39. OUT5_CLEAR_CODE Register Field Descriptions

7.1.39 OUT6_CLEAR_CODE Register (Offset = 26h) [Reset = 0000h] Figure 7-39. OUT6_CLEAR_CODE Register

Table 7-40. OUT6_CLEAR_CODE Register Field Descriptions

7.1.40 OUT7_CLEAR_CODE Register (Offset = 27h) [Reset = 0000h] Figure 7-40. OUT7_CLEAR_CODE Register

Table 7-41. OUT7_CLEAR_CODE Register Field Descriptions

7.1.41 OUT8_CLEAR_CODE Register (Offset = 28h) [Reset = 0000h] Figure 7-41. OUT8_CLEAR_CODE Register

Table 7-42. OUT8_CLEAR_CODE Register Field Descriptions

7.1.42 OUT9_CLEAR_CODE Register (Offset = 29h) [Reset = 0000h] Figure 7-42. OUT9_CLEAR_CODE Register

Table 7-43. OUT9_CLEAR_CODE Register Field Descriptions

7.1.43 OUT10_CLEAR_CODE Register (Offset = 2Ah) [Reset = 0000h] Figure 7-43. OUT10_CLEAR_CODE Register

Table 7-44. OUT10_CLEAR_CODE Register Field Descriptions

7.1.44 OUT11_CLEAR_CODE Register (Offset = 2Bh) [Reset = 0000h] Figure 7-44. OUT11_CLEAR_CODE Register

Table 7-45. OUT11_CLEAR_CODE Register Field Descriptions

7.1.45 OUT12_CLEAR_CODE Register (Offset = 2Ch) [Reset = 0000h] Figure 7-45. OUT12_CLEAR_CODE Register

Table 7-46. OUT12_CLEAR_CODE Register Field Descriptions

7.1.46 OUT13_CLEAR_CODE Register (Offset = 2Dh) [Reset = 0000h] Figure 7-46. OUT13_CLEAR_CODE Register

Table 7-47. OUT13_CLEAR_CODE Register Field Descriptions

7.1.47 OUT14_CLEAR_CODE Register (Offset = 2Eh) [Reset = 0000h] Figure 7-47. OUT14_CLEAR_CODE Register

Table 7-48. OUT14_CLEAR_CODE Register Field Descriptions

7.1.48 OUT15_CLEAR_CODE Register (Offset = 2Fh) [Reset = 0000h] Figure 7-48. OUT15_CLEAR_CODE Register

Table 7-49. OUT15_CLEAR_CODE Register Field Descriptions

7.1.49 GPIO_DATA Register (Offset = 31h) [Reset = 0001h] Figure 7-49. GPIO_DATA Register

Table 7-50. GPIO_DATA Register Field Descriptions

7.1.50 DAC_STATUS Register (Offset = 32h) [Reset = 0000h] Figure 7-50. DAC_STATUS Register

Table 7-51. DAC_STATUS Register Field Descriptions

Table 7-51. DAC_STATUS Register Field Descriptions (continued)

8 Application and Implementation

Note

Information in the following applications sections is not part of the TI component specification, and TI does not warrant its accuracy or completeness. TI's customers are responsible for determining suitability of components for their purposes, as well as validating and testing their design implementation to confirm system functionality.

8.1 Application Information

The high linearity, small package size, and wide temperature range make the DAC80516 an excellent choice in applications such as optical networking, wireless infrastructure, and analog output modules for industrial systems. The device incorporates a 2.5V internal reference with an internal reference divider circuit that enables full-scale DAC output voltages of 2.5V or 5V.

8.1.1 Bipolar Voltage Output

While the DAC80516 is designed for single-supply operation, Figure 8-1 shows that a bipolar output is also possible.

Figure 8-1. Bipolar Operation Using the DAC80516

The circuit in Figure 8-1 gives a bipolar output voltage at V_{OUTPUT} which is calculated as follows (at gain = 1):

$$
V_{\text{OUTPUT}}(\text{CODE}) = \left[\left(V_{\text{REF}} \times \frac{\text{CODE}}{2^{16}} \right) \left(1 + \frac{R_3}{R_2} + \frac{R_3}{R_1} \right) - \left(V_{\text{REF}} \times \frac{R_3}{R_1} \right) \right]
$$
(2)

where

- V_{OUTPUT} (CODE) = output voltage of circuit for a given code
- $CODE = 0$ to 65535. This is the digital code loaded to the DAC
- V_{REF} = reference voltage applied to the DAC80516

The bipolar output span can be calculated through Equation 2 by defining a few parameters, the first being the value for the reference voltage. After a reference voltage is chosen, the gain resistors can be set accordingly by determining the desired V_{OUTPUT} at code 0 and code 65536. For a V_{REF} of 2.5V, gain of 1, and a desired output voltage range of ±10V, the calculation is as follows.

 $CODE = 0$:

$$
V_{\text{OUTPUT}}(0) = -\left(V_{\text{REF}} \times \frac{R_3}{R_1}\right) = -\left(2.5V \times \frac{R_3}{R_1}\right) \tag{3}
$$

Setting the equation to minimum output span, $V_{\text{OUTPI}}(0) = -10V$, reduces the equation to: R₃ / R₁ = 4.

CODE = 65536:

Setting the equation to maximum output scan, $V_{\text{OUTPUT}}(65536) = 10V$, and R₃ / R₁ = 4 reduces the equation to: $R_3 / R_2 = 3$

The maximum code of a 16-bit DAC is 65535; code 65536 is used to simplify Equation 3. For practical use, the true output span uses a range of –10V to (10V – 1LSB); in this case, –10V to +9.9996V.

8.2 Typical Application

8.2.1 Programmable High-Current Voltage Output Circuit

While the DAC80516 is capable of driving currents up to 50mA (with a short circuit current rating of 75mA), the device can be integrated into the circuit in Figure 8-2 to achieve a stable voltage output with even higher drive currents. In this application, the DAC programs the output voltage and gain of an amplifier. The amplifier maintains the output voltage using negative feedback. The high current to the load is provided by the transistor. This circuit is useful in applications where components must be tested with different voltage excitation levels at higher currents, including optical laser biasing applications (requiring over 50mA-75mA of bias current) as well as semiconductor test equipment.

Figure 8-2. Programmable Voltage-Controlled Current Source Circuit

8.2.1.1 Design Requirements

An op amp with low offset and low drift (to minimize error) and sufficient gain bandwidth product (GBW) is recommended. R_1 and R_2 must have sufficient tolerance so that the desired output voltage (V_{OUTPUT}) accurately follows the DAC output voltage. Compensation capacitor C_1 must be larger than the input capacitance of the op-amp inputs. Choose a transistor that can provide the required load current and has a high H_{FE} , so that the base current is sufficiently smaller than the output current limit of the op amp. A bipolar-junction transistor (BJT) Darlington pair or a high-power metal-oxide semiconductor field-effect transistor (MOSFET) can be used.

8.2.1.2 Detailed Design Procedure

The transfer function of the output voltage is given by Equation 4.

$$
V_{\text{OUTPUT}} = V_{\text{DAC}} \left(1 + \frac{R_1}{R_2} \right) \tag{4}
$$

The resistance values can be chosen so that the quiescent current is negligible compared to the load current. For a desired load current of 10A at a desired V_{OUTPUT} of 5V (with V_{DAC} = 2.5V), choose R₁ and R₂ as 10kΩ each. This minimizes the quiescent current through the feedback network as 5V / 20k Ω = 250µA.

The base current, I_B , for the transistor for a given load current I_L is given by Equation 5.

$$
I_{B} = \frac{I_{C}}{H_{FE}} = \frac{1}{H_{FE}} \left(I_{L} + \left(\frac{V_{OUTPUT}}{R_{1} + R_{2}} \right) \right)
$$
(5)

Where:

- \cdot I_C = The collector current of the transistor
- H_{FE} = DC current gain of the transistor

 V_{OUTPUT} / (R_1+R_2) is equal to the previously calculated quiescent current, which is negligible compared to the load current (particularly for load currents above 1A). This simplifies the equation to Equation 6.

$$
I_B = \frac{I_L}{H_{FE}} \tag{6}
$$

To keep I_B less than 20mA, H_{FE} must be greater than I_L / 20mA. In general, compensation capacitor C₁ is not set by fixed equations, but rather by choosing values while observing the output small-signal step response.

8.2.1.3 Application Curve

Figure 8-3 shows the headroom curve for the DAC80516 when using the internal reference at gain = 2 (AV_{DD} = 5.5V). This curve illustrates how the DAC channels are able to maintain output voltage as load current increases.

Figure 8-3. Headroom vs Load Current

8.3 Initialization Setup

Power on the device and ensure that the AV_{DD} and V_{IO} supplies are established. After the supplies have reached the minimum recommended operating value, a POR is issued so that the device initializes correctly. The DAC80516 requires 5ms to 10ms to initialize the serial interface after a POR; therefore, wait at least 10ms after start-up to communicate with the device.

8.4 Power Supply Recommendations

The DAC80516 operate within the specified AV_{DD} supply range of 2.7V to 5.5V and V_{IO} supply range of 1.7V to 5.5V. The DAC80516 does not require specific supply sequencing; however the serial interface requires 10ms to initialize and enable communication with the device.

The AV_{DD} supply must be well-regulated and low-noise. Switching power supplies and DC/DC converters often have high-frequency glitches or spikes riding on the output voltage. In addition, digital components can create similar high frequency spikes. This noise can easily couple into the DAC output voltage through various paths between the power connections and analog output. To minimize noise from the power supply, include a 1µF to 10μF capacitor and 0.1μF bypass capacitor. The power supply must meet the input current requirements listed in *[Section 5](#page-3-0)*.

8.5 Layout

8.5.1 Layout Guidelines

A precision analog component requires careful layout, the list below provides some insight into good layout practices.

- Bypass all power supply pins to ground with a low ESR ceramic bypass capacitor. The typical recommended bypass capacitance is 0.1µF to 0.22µF ceramic with a X7R or NP0 dielectric.
- Place power supplies and REF bypass capacitors close to the pins to minimize inductance and optimize performance.
- Use a high-quality, ceramic, type NP0 or X7R for optimized performance across temperature, and very low dissipation factor.
- The digital and analog sections must have proper placement with respect to the digital pins and analog pins of the DAC80516 device. The separation of analog and digital blocks minimizes coupling into neighboring blocks, as well as interaction between analog and digital return currents.

8.5.2 Layout Examples

Figure 8-4. DAC80516 QFN Layout Example

9 Device and Documentation Support

9.1 Documentation Support

Note

TI is transitioning to use more inclusive terminology. Some language can be different than what is expected for certain technology areas.

9.1.1 Related Documentation

For related documentation see the following:

• Texas Instruments, [DAC80516EVM user guide](https://www.ti.com/lit/pdf/SLAU916)

9.2 Receiving Notification of Documentation Updates

To receive notification of documentation updates, navigate to the device product folder on [ti.com.](https://www.ti.com) Click on *Notifications* to register and receive a weekly digest of any product information that has changed. For change details, review the revision history included in any revised document.

9.3 Support Resources

TI E2E™ [support forums](https://e2e.ti.com) are an engineer's go-to source for fast, verified answers and design help — straight from the experts. Search existing answers or ask your own question to get the quick design help you need.

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9.4 Trademarks

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9.5 Electrostatic Discharge Caution

This integrated circuit can be damaged by ESD. Texas Instruments recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedures can cause damage.

ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

9.6 Glossary

[TI Glossary](https://www.ti.com/lit/pdf/SLYZ022) This glossary lists and explains terms, acronyms, and definitions.

10 Revision History

NOTE: Page numbers for previous revisions may differ from page numbers in the current version.

11 Mechanical, Packaging, and Orderable Information

The following pages include mechanical, packaging, and orderable information. This information is the most current data available for the designated devices. This data is subject to change without notice and revision of this document. For browser-based versions of this data sheet, refer to the left-hand navigation.

PACKAGING INFORMATION

(1) The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBSOLETE: TI has discontinued the production of the device.

⁽²⁾ RoHS: TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".

RoHS Exempt: TI defines "RoHS Exempt" to mean products that contain lead but are compliant with EU RoHS pursuant to a specific EU RoHS exemption.

Green: TI defines "Green" to mean the content of Chlorine (CI) and Bromine (Br) based flame retardants meet JS709B low halogen requirements of <=1000ppm threshold. Antimony trioxide based flame retardants must also meet the <=1000ppm threshold requirement.

(3) MSL, Peak Temp. - The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

(4) There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.

(5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.

(6) Lead finish/Ball material - Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

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RUY0028A

PACKAGE OUTLINE

WQFN - 0.8 mm max height

PLASTIC QUAD FLATPACK-NO LEAD

NOTES:

- per ASME Y14.5M.
This drawing is subject to change without notice.
-
-

EXAMPLE BOARD LAYOUT

RUY0028A WQFN - 0.8 mm max height

PLASTIC QUAD FLATPACK-NO LEAD

NOTES: (continued)

-
- on this view. It is recommended that vias under paste be filled, plugged or tented.

EXAMPLE STENCIL DESIGN

RUY0028A WQFN - 0.8 mm max height

PLASTIC QUAD FLATPACK-NO LEAD

NOTES: (continued)

6. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.

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